

Electrochemical Reduction of NO on ZnO and In₂O₃ Semiconductor Electrodes in Aqueous K₂SO₄ Solutions

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NO was efficiently reduced on ZnO and In₂O₃ of n-type semiconductor electrodes in aqueous solutions. Harmless N₂ was obtained as a main reduction product. Current-potential curves on the ZnO and In₂O₃ electrodes under NO were quite similar to those under N₂O. It is proposed that the NO reduction on the ZnO and In₂O₃ electrodes proceeds via the redox mechanism in which oxygen vacancies formed by the electrochemical reduction on the electrode surface play an important role.

Activation of NO is of interest from the view points of catalyses and emission control. Thermal catalytic reduction of NO by reducing reagents such as NH₃, CO, and hydrocarbons has extensively been studied for a long time.¹ On the other hand, the number of reports on the electrochemical reduction of NO is not so large.²⁻⁸ Moreover, in most studies on the electrochemical NO reduction, platinum has been employed as an electrode material in acidic solutions. In contrast, oxide electrodes have hardly been used for this reaction. Unique electrocatalyses of the oxide electrodes will be expected because the oxides often possess various properties for thermal catalyses. The authors have reported the electrochemical reduction of N₂O on oxide semiconductor electrodes such as ZnO and In₂O₃.^{9,10} The reduction product of N₂O is only N₂. In the case of the electrochemical NO reduction, however, some reduction products such as N₂, N₂O, and NH₃ are obtained. The selectivity of the reduction products can be argued. Therefore, NO reduction is an interesting system for studying catalyses on electrode surfaces as well as CO₂ reduction.¹¹⁻¹³

This paper reports the efficient reduction of NO on ZnO and In₂O₃ of n-type semiconductor electrodes. The mechanism of the surface reaction on the electrodes is discussed by comparison of the electrochemical reduction of NO with that of N₂O reported previously.

Sintered polycrystalline ZnO (Kanto Chemical, purity: 99.0%), In₂O₃ (Kanto Chemical, purity: 99.9%), and In³⁺-doped ZnO electrodes were prepared by heating pressed disks of the powder at 1370 K for 10 h in air using an alumina crucible. An ordinary H-type cell where catholytes were separated from anolytes with Nafion 417^R was employed. The electrolyte was an aqueous K₂SO₄ solution (0.3 mol dm⁻³). A Pt black plate and Ag | AgCl | KCl (sat.) were used as counter and reference electrodes, respectively. The electrode potentials are noted with respect to the Ag | AgCl | KCl (sat.) reference electrode. The electrolyses were carried out with agitation galvanostatically using a potentiostat-galvanostat (Hokuto; model HZ3000) after current-potential curve measurements under Ar and NO. Ar and NO (purity: 99%) gases were used without further purification. Gaseous products were determined using gas chromatography. MS5A column, TCD detector, and Ar carrier were used for H₂ and N₂ analyses and PPQ column, TCD detector and He carrier were employed for N₂O analyses. The amount of NH₃ formed

was determined by the Indophenol method¹⁴ using a spectrometer (JASCO; Ubest V-570).

Figure 1 shows the current-potential curves of ZnO electrodes under Ar and NO in aqueous K₂SO₄ solutions. Under NO, the cathodic current arose at -1.0 V and a characteristic reduction wave was observed around -1.4 V during sweeping negatively. Figure 2 shows the current-potential curves of In₂O₃ electrodes under Ar and NO. The characteristic difference between Ar and NO condition as seen for ZnO electrodes was not observed for

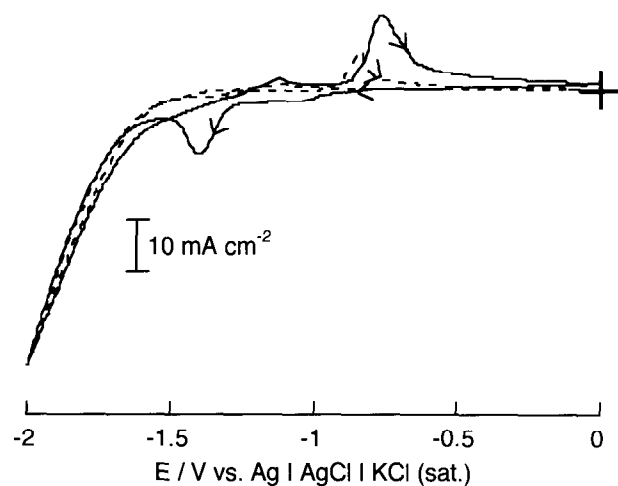


Figure 1. Cyclic voltammograms of ZnO sintered electrodes in aqueous K₂SO₄ solutions (0.3 mol dm⁻³). Dashed line; under Ar, solid line; under NO, sweep rate: 50 mV/s.

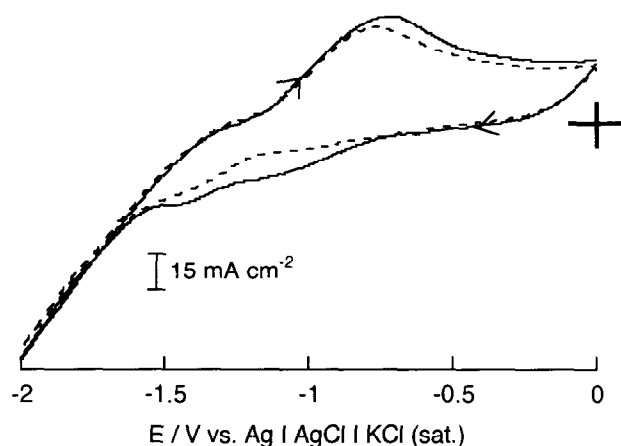


Figure 2. Cyclic voltammograms of In₂O₃ sintered electrodes in aqueous K₂SO₄ solutions (0.3 mol dm⁻³). Dashed line; under Ar, solid line; under NO, sweep rate: 50 mV/s.

Table 1. Efficiencies of electrochemical reduction of NO on oxide semiconductor electrodes at 13 mA cm⁻² in aqueous K₂SO₄ solutions at 300 K

Electrode	Potential / V ^a	Faradaic efficiency / %				
		N ₂ O	N ₂	NH ₃	H ₂	Total
ZnO	-1.65 → -1.55	11	53	27	2	93
In ₂ O ₃	-0.96 → -1.43	6	77	13	2	98
In ³⁺ (1 mol%)-ZnO	-1.3 → -1.5	17	73	22	6	118

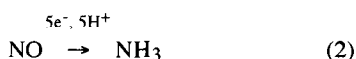
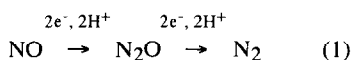
^a vs. an Ag | AgCl | KCl-sat. reference electrode. Charge passed: 130C.

the In₂O₃ electrode although the cathodic current in the region between -0.8 and -1.5 V under NO was slightly larger than that under Ar. The behavior on the current-potential curves on the ZnO and In₂O₃ under NO was quite similar to that under N₂O.⁹ This result suggests that the active site on the electrode surface for the NO reduction may be the same as that for the N₂O reduction. The current-potential curves of ZnO and In₂O₃ electrodes are divided into two regions at ca. -1.6 V. Steep curves of the cathodic current are observed at the region more negative than ca. -1.6 V while the curves with gentle slopes are obtained at less negative than ca. -1.6 V. At the latter region, the increase in cathodic currents under NO is observed compared with that under Ar for ZnO and In₂O₃ electrodes. The electrode surfaces are reduced more or less at this potential region. These observations suggest that the active site may be an oxygen vacancy.

Table 1 shows the efficiencies of electrochemical reduction of NO on ZnO, In₂O₃, and In³⁺(1 mol%)-doped ZnO electrodes at 13 mA cm⁻² of a constant current density in aqueous K₂SO₄ solutions. NO was reduced with high Faradaic efficiencies. The main reduction product was harmless N₂ rather than NH₃. H₂ formation which should compete with the NO reduction in aqueous solutions was negligible. Electrode potentials of ZnO and In³⁺(1 mol%)-doped ZnO electrodes were stable during electrolyses. In contrast, the electrode potential of In₂O₃ drastically changed from -0.96 V to -1.43 V at the initial stage of electrolyses. In this process, the In₂O₃ electrode is probably reduced to form oxides with low oxidation numbers such as In₂O. The electrochemical reduction of NO might proceed on such a surface.

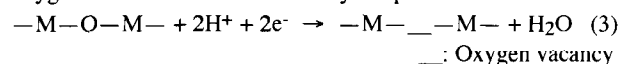
The electrochemical reduction of NO has mainly been conducted on Pt electrodes in acidic aqueous solutions so far.^{2-4,6-8} In these cases, NH₃, NH₂OH and N₂O have been obtained as main reduction products, depending on the electrolysis condition. It is noteworthy that, in the present study, N₂ was efficiently formed by using some oxide semiconductor electrodes which have not been employed for this reaction.

Two paths can mainly be considered for the electrochemical NO reduction as follows.

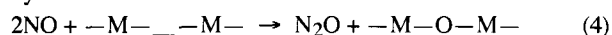


The path (1) is a reduction reaction accompanied with the N-N bond formation. The path (2) is a hydrogenation reaction. The main product was N₂ on ZnO, In₂O₃, and In³⁺(1 mol%)-doped ZnO electrodes showing that the main reaction might proceed via the path (1). It has been reported that an oxygen vacancy plays an important role for the adsorption and activation of NO molecules on oxide surfaces such as ZnO in gas phase.¹⁵ When

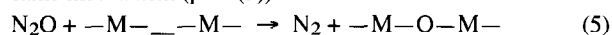
reducible oxide electrodes with an n-type semiconductor characteristic such as ZnO and In₂O₃ are polarized negatively, oxygen vacancies can be formed by the partial reduction.



If the oxygen vacancy works as the active site for the NO reduction, a deoxygen reaction shown in the path (4) is favorable to hydrogenation. In this path, the oxide surfaces are reoxidized by NO.



N₂O formed in the path (4) can subsequently be reduced by the same mechanism (path (5)).



It has been reported that the electrochemical N₂O reduction efficiently proceeds on ZnO, In₂O₃, and In³⁺(1 mol%)-doped ZnO electrodes in an aqueous solution.^{9,10} The highly efficiency for the electrochemical reduction of NO and selective formation of N₂ rather than NH₃ are thought to be due to the redox mechanism accompanied with oxygen vacancies formed by electrochemical reduction of the n-type semiconductor oxide electrode surfaces via paths (3)-(5).

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